



Inventor Name Search Result

Your Search was:

Last Name = HONDA

First Name = TOSHIKUMI

Application#	Patent#	Status	Date Filed	Title	Inventor Name
08967015	6333992	150	11/10/1997	DEFECT JUDGEMENT PROCESSING METHOD AND APPARATUS	HONDA, TOSHIKUMI
✓					
08968125	6249598	150	11/12/1997	SOLDER TESTING APPARATUS	HONDA, TOSHIKUMI
09413468	6622054	150	10/06/1999	METHOD MONITORING A QUALITY OF ELECTRONIC CIRCUITS AND ITS MANUFACTURING CONDITION AND SYSTEM FOR IT	HONDA, TOSHIKUMI
✓					
09661182	6553323	150	09/13/2000	METHOD AND ITS APPARATUS FOR INSPECTING A SPECIMEN	HONDA, TOSHIKUMI
✓					
10081782	7181060	150	02/20/2002	DEFECT INSPECTION METHOD	HONDA, TOSHIKUMI
✓					
10224087	6965429	150	08/19/2002	METHOD OF REVIEWING DETECTED DEFECTS	HONDA, TOSHIKUMI
10256585	6855930	150	09/27/2002	DEFECT INSPECTION APPARATUS AND DEFECT INSPECTION METHOD	HONDA, TOSHIKUMI
✓					
10378016	Not Issued	71	02/28/2003	Method and its apparatus for classifying defects	HONDA, TOSHIKUMI
✓					
10640343	Not Issued	71	08/12/2003	Defect inspection method	HONDA, TOSHIKUMI
✓					
10762091	Not Issued	71	01/20/2004	Method of classifying defects	HONDA, TOSHIKUMI
✓					
10794267	Not Issued	41	03/04/2004	Defect classification method	HONDA, TOSHIKUMI
✓					
10809464	Not Issued	61	03/26/2004	Method and its apparatus for classifying defects	HONDA, TOSHIKUMI
✓					
10954421	Not Issued	71	10/01/2004	Method of observing defects	HONDA, TOSHIKUMI
✓					

11020255	710581S	150	12/27/2004	METHOD AND APPARATUS FOR COLLECTING DEFECT IMAGES	HONDA, TOSHIKUMI
11020265	7075077	150	12/27/2004	METHOD OF OBSERVING A SPECIMEN USING A SCANNING ELECTRON MICROSCOPE	HONDA, TOSHIKUMI
11042021	7205555	150	01/24/2005	DEFECT INSPECTION APPARATUS AND DEFECT INSPECTION METHOD	HONDA, TOSHIKUMI
11130121	7361896	150	05/17/2005	SCANNING ELECTRON MICROSCOPE AND A METHOD FOR ADJUSTING A FOCAL POINT OF AN ELECTRON BEAM OF SAID SCANNING ELECTRON MICROSCOPE	HONDA, TOSHIKUMI
11190829	Not Issued	30	07/28/2005	Method and its apparatus for classifying defects	HONDA, TOSHIKUMI
11248697	7170593	150	10/11/2005	METHOD OF REVIEWING DETECTED DEFECTS	HONDA, TOSHIKUMI
11268568	Not Issued	41	11/08/2005	Scanning electron microscope and system for inspecting semiconductor device	HONDA, TOSHIKUMI
11311254	Not Issued	30	12/20/2005	Method and apparatus for reviewing defects	HONDA, TOSHIKUMI
11319721	Not Issued	71	12/29/2005	Scanning electron microscope and method for detecting an image using the same	HONDA, TOSHIKUMI
11325582	Not Issued	30	01/05/2006	Method and apparatus for reviewing defects	HONDA, TOSHIKUMI
11415286	Not Issued	30	05/02/2006	Observing method and its apparatus using electron microscope	HONDA, TOSHIKUMI
11488636	Not Issued	30	07/19/2006	Method and apparatus for reviewing defects of semiconductor device	HONDA, TOSHIKUMI
11634963	Not Issued	30	12/07/2006	Method and apparatus of reviewing defects on a semiconductor device	HONDA, TOSHIKUMI
11668510	Not Issued	30	01/30/2007	METHOD AND APPARATUS FOR REVIEWING DEFECTS	HONDA, TOSHIKUMI
11677669	Not Issued	30	02/22/2007	METHOD AND APPARATUS FOR DISPLAYING DETECTED DEFECTS	HONDA, TOSHIKUMI

11704228 ✓	Not Issued	51	02/09/2007	Method and apparatus for reviewing defects by detecting images having voltage contrast	HONDA, TOSHIKUMI
11704350 ✓	Not Issued	30	02/09/2007	Method and apparatus for reviewing defects	HONDA, TOSHIKUMI
11747253 ✓	Not Issued	25	05/11/2007	SFM-TYPE REVIEWING APPARATUS AND A METHOD FOR REVIEWING DEFECTS USING THE SAME	HONDA, TOSHIKUMI
11779937 ✓	Not Issued	30	07/19/2007	REVIEWING APPARATUS USING A SEM AND METHOD FOR REVIEWING DEFECTS OR DETECTING DEFECTS USING THE REVIEWING APPARATUS	HONDA, TOSHIKUMI
12033470 ✓	Not Issued	19	01/01/0001	DEFECT REVIEW METHOD AND DEVICE FOR SEMICONDUCTOR DEVICE	HONDA, TOSHIKUMI

Inventor Search Completed: No Records to Display.

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PALM INTRANET**Inventor Name Search Result**

Your Search was:

Last Name = OKUDA

First Name = HIROHITO

Application#	Patent#	Status	Date Filed	Title	Inventor Name
09413468	6622054	150	10/06/1999	METHOD MONITORING A QUALITY OF ELECTRONIC CIRCUITS AND ITS MANUFACTURING CONDITION AND SYSTEM FOR IT	OKUDA, HIROHITO
10080519	7231079	150	01/18/2002	METHOD AND SYSTEM FOR INSPECTING ELECTRONIC CIRCUIT PATTERN	OKUDA, HIROHITO
10681782	7181060	150	02/20/2002	DEFECT INSPECTION METHOD	OKUDA, HIROHITO
10224087	6965429	150	08/19/2002	METHOD OF REVIEWING DETECTED DEFECTS	OKUDA, HIROHITO
10256585	6885930	150	09/27/2002	DEFECT INSPECTION APPARATUS AND DEFECT INSPECTION METHOD	OKUDA, HIROHITO
10378016	Not Issued	71	02/28/2003	Method and its apparatus for classifying defects	OKUDA, HIROHITO
10640343	Not Issued	71	08/12/2003	Defect inspection method	OKUDA, HIROHITO
10762091	Not Issued	71	01/20/2004	Method of classifying defects	OKUDA, HIROHITO
10794267	Not Issued	41	03/04/2004	Defect classification method	OKUDA, HIROHITO
10809464	Not Issued	61	03/26/2004	Method and its apparatus for classifying defects	OKUDA, HIROHITO
10918340	7634299	150	08/16/2004	TRANSMISSION ELECTRON MICROSCOPE SYSTEM AND METHOD OF INSPECTING A SPECIMEN USING THE SAME	OKUDA, HIROHITO
11020265	7075077	150	12/27/2004	METHOD OF OBSERVING A SPECIMEN USING A	OKUDA, HIROHITO

				SCANNING ELECTRON MICROSCOPE	
11042921	7205555	150	01/24/2005	DEFECT INSPECTION APPARATUS AND DEFECT INSPECTION METHOD	OKUDA, HIROHITO
	✓				
11243697	7170593	150	10/11/2005	METHOD OF REVIEWING DETECTED DEFECTS	OKUDA, HIROHITO
	✓				
11478618	Not Issued	30	07/03/2006	Apparatus and method for electron beam inspection with projection electron microscopy	OKUDA, HIROHITO
11488734	Not Issued	30	07/19/2006	Method and apparatus for inspecting defects of circuit patterns	OKUDA, HIROHITO
	✓				
11601723	Not Issued	30	11/20/2006	Method and apparatus for inspecting pattern defects and mirror electron projection Type or multi-beam scanning type electron beam apparatus	OKUDA, HIROHITO
	✓				

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